## Daniel F Sunday

List of Publications by Year in descending order

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#	Article	IF	CITATIONS
1	Determination of the Internal Morphology of Nanostructures Patterned by Directed Self Assembly. ACS Nano, 2014, 8, 8426-8437.	7.3	58
2	Determining the shape and periodicity of nanostructures using small-angle X-ray scattering. Journal of Applied Crystallography, 2015, 48, 1355-1363.	1.9	53
3	Thermal and Rheological Behavior of Polymer Grafted Nanoparticles. Macromolecules, 2015, 48, 8651-8659.	2.2	43
4	Self-Assembly of ABC Bottlebrush Triblock Terpolymers with Evidence for Looped Backbone Conformations. Macromolecules, 2018, 51, 7178-7185.	2.2	40
5	Reducing Block Copolymer Interfacial Widths through Polymer Additives. Macromolecules, 2015, 48, 679-686.	2.2	34
6	Characterizing the Interface Scaling of High χ Block Copolymers near the Order–Disorder Transition. Macromolecules, 2018, 51, 173-180.	2.2	34
7	Three-dimensional x-ray metrology for block copolymer lithography line-space patterns. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2013, 12, 031103.	1.0	33
8	Template–polymer commensurability and directed selfâ€assembly block copolymer lithography. Journal of Polymer Science, Part B: Polymer Physics, 2015, 53, 595-603.	2.4	26
9	Derivation of Multiple Covarying Material and Process Parameters Using Physics-Based Modeling of X-ray Data. Macromolecules, 2017, 50, 7783-7793.	2.2	26
10	Advancing x-ray scattering metrology using inverse genetic algorithms. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2016, 15, 034001.	1.0	24
11	Confinement and Processing Can Alter the Morphology and Periodicity of Bottlebrush Block Copolymers in Thin Films. ACS Nano, 2020, 14, 17476-17486.	7.3	19
12	Concentration Dependence of the Size and Symmetry of a Bottlebrush Polymer in a Good Solvent. Macromolecules, 2020, 53, 7132-7140.	2.2	19
13	Influence of Additives on the Interfacial Width and Line Edge Roughness in Block Copolymer Lithography. Chemistry of Materials, 2020, 32, 2399-2407.	3.2	17
14	Evaluation of the effect of data quality on the profile uncertainty of critical dimension small angle x-ray scattering. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2016, 15, 014001.	1.0	16
15	Functional group quantification of polymer nanomembranes with soft x-rays. Physical Review Materials, 2018, 2, .	0.9	16
16	Optimizing self-consistent field theory block copolymer models with X-ray metrology. Molecular Systems Design and Engineering, 2018, 3, 376-389.	1.7	13
17	Intercomparison between optical and x-ray scatterometry measurements of FinFET structures. , 2013, , .		12
18	Quantifying the Interface Energy of Block Copolymer Top Coats. ACS Macro Letters, 2016, 5, 1306-1311.	2.3	12

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19	Polarized X-ray scattering measures molecular orientation in polymer-grafted nanoparticles. Nature Communications, 2021, 12, 4896.	5.8	11
20	Characterizing Patterned Block Copolymer Thin Films with Soft X-rays. ACS Applied Materials & Interfaces, 2017, 9, 31325-31334.	4.0	10
21	Molecular Orientation Depth Profiles in Organic Glasses Using Polarized Resonant Soft X-ray Reflectivity. Chemistry of Materials, 2020, 32, 6295-6309.	3.2	10
22	X-ray scattering critical dimensional metrology using a compact x-ray source for next generation semiconductor devices. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2017, 16, 014001.	1.0	9
23	Addressing the challenges of modeling the scattering from bottlebrush polymers in solution. Journal of Polymer Science, 2020, 58, 988-996.	2.0	8
24	Thermodynamic and Morphological Behavior of Block Copolymer Blends with Thermal Polymer Additives. Macromolecules, 2016, 49, 4898-4908.	2.2	7
25	Spatial Control of the Self-assembled Block Copolymer Domain Orientation and Alignment on Photopatterned Surfaces. ACS Applied Materials & amp; Interfaces, 2020, 12, 23399-23409.	4.0	7
26	Characterization of the Interfacial Orientation and Molecular Conformation in a Glass-Forming Organic Semiconductor. ACS Applied Materials & amp; Interfaces, 2022, 14, 3455-3466.	4.0	5
27	X-ray characterization of contact holes for block copolymer lithography. Journal of Applied Crystallography, 2019, 52, 106-114.	1.9	3
28	Methodology for evaluating the information distribution in small angle scattering from periodic nanostructures. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2018, 17, 1.	1.0	3
29	Self-Assembly of ABC Bottlebrush Triblock Terpolymers with Evidence for Looped Backbone Conformations. Macromolecules, 2018, 51, .	2.2	3
30	Modeling the polarized X-ray scattering from periodic nanostructures with molecular anisotropy. Journal of Applied Crystallography, 2017, 50, 1677-1690.	1.9	2
31	Buried Structure in Block Copolymer Films Revealed by Soft X-ray Reflectivity. ACS Nano, 2021, 15, 9577-9587.	7.3	2
32	Compact X-ray Sources for Metrology Applications in the Semiconductor Industry. , 2016, , .		1
33	The Influence of Additives on the Interfacial Width and Line Edge Roughness in Block Copolymer Lithography. Chemistry of Materials, 2020, 32, .	3.2	1
34	X-ray Metrology for the SemiconductorIndustry Tutorial. Journal of Research of the National Institute of Standards and Technology, 2019, 124, 1-3.	0.4	0
35	X-ray characterization of contact holes for block copolymer lithography. Journal of Applied Crystallography, 2019, 52, .	1.9	0
36	Methodology for evaluating the information distribution in small angle scattering from periodic nanostructures. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2018, 17, .	1.0	0